


<b>Search Notes</b>  	<b>Application/Control No.</b>  10511626	<b>Applicant(s)/Patent Under Reexamination</b>  NIHEI ET AL.
	<b>Examiner</b>  Mack, Chanelle N	<b>Art Unit</b>  2609

SEARCHED			
Class	Subclass	Date	Examiner
345	84-85, 107	07/23/2007	C. Mack
359	296	07/23/2007	C. Mack

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner